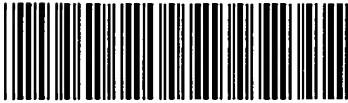


Search Notes

Application/Control No.

10/727,171

Examiner

James D. Stein

Applicant(s)/Patent under
Reexamination

MIZUNO ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385	14,15,24	12/15/2005	JDS
385	39,40,49	12/15/2005	JDS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	12/15/2005	JDS
IEEE INSPEC: MZI, AWG, phase, quadratic, MUX, DMUX	12/15/2005	JDS